

**ROCHESTER INSTITUTE OF TECHNOLOGY  
MICROELECTRONIC ENGINEERING**

# Factory Products

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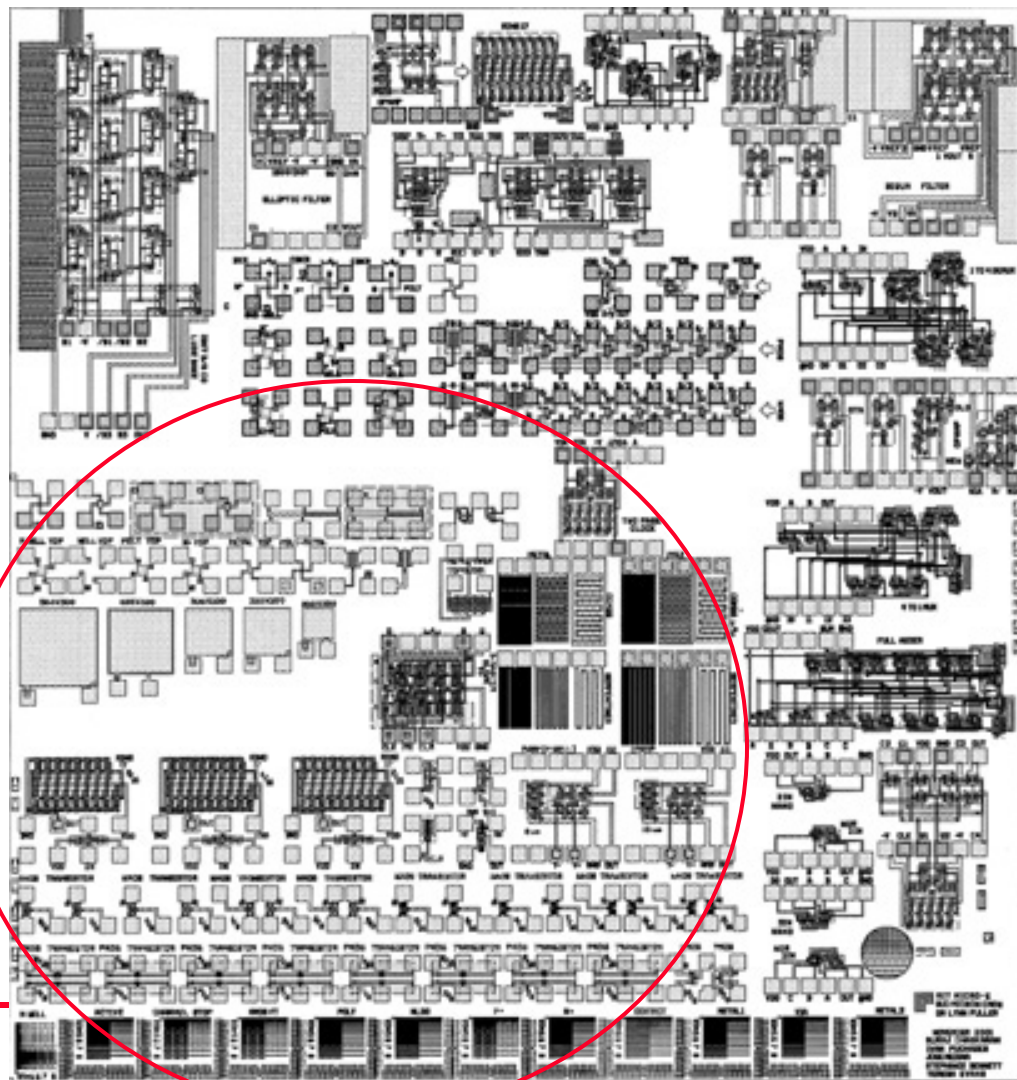
# *PRODUCTS*

Mixed Analog/Digital Test Chip (Sub-CMOS Process)  
Test Chip (Advanced CMOS Process)  
SPICE Parametric Test Chip (SMFL CMOS Process)  
DAC 2003 Project Chip (SMFL CMOS Process)  
John Gault Test Chip (Sub-CMOS Process)

The pictures on the following pages are too small to show the detail needed to see the test structures. Large printouts of the various products have been posted on the walls in the test lab to aid in locating the test structures.

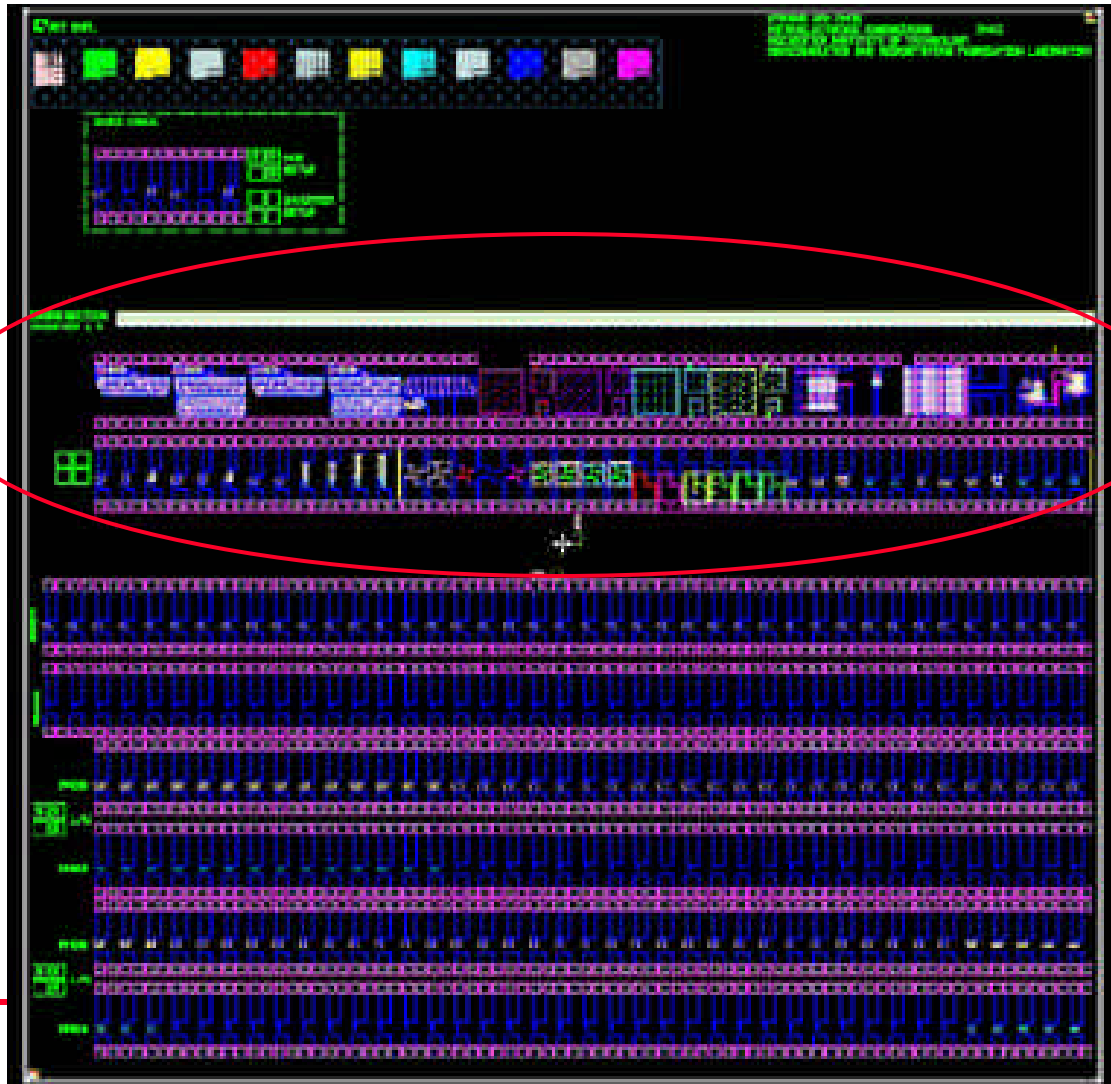
## *MIXED ANALOG/DIGITAL CMOS TEST CHIP*

Layout of CMOS test chip for microelectronic engineering manufacturing courses. This chip has transistors down to  $0.5\ \mu\text{m}$  gate length, a variety of test structures, digital and analog circuit building blocks including A-to-D and D-to-A converters, operational amplifiers, transconductance amplifiers, and filters of various types.

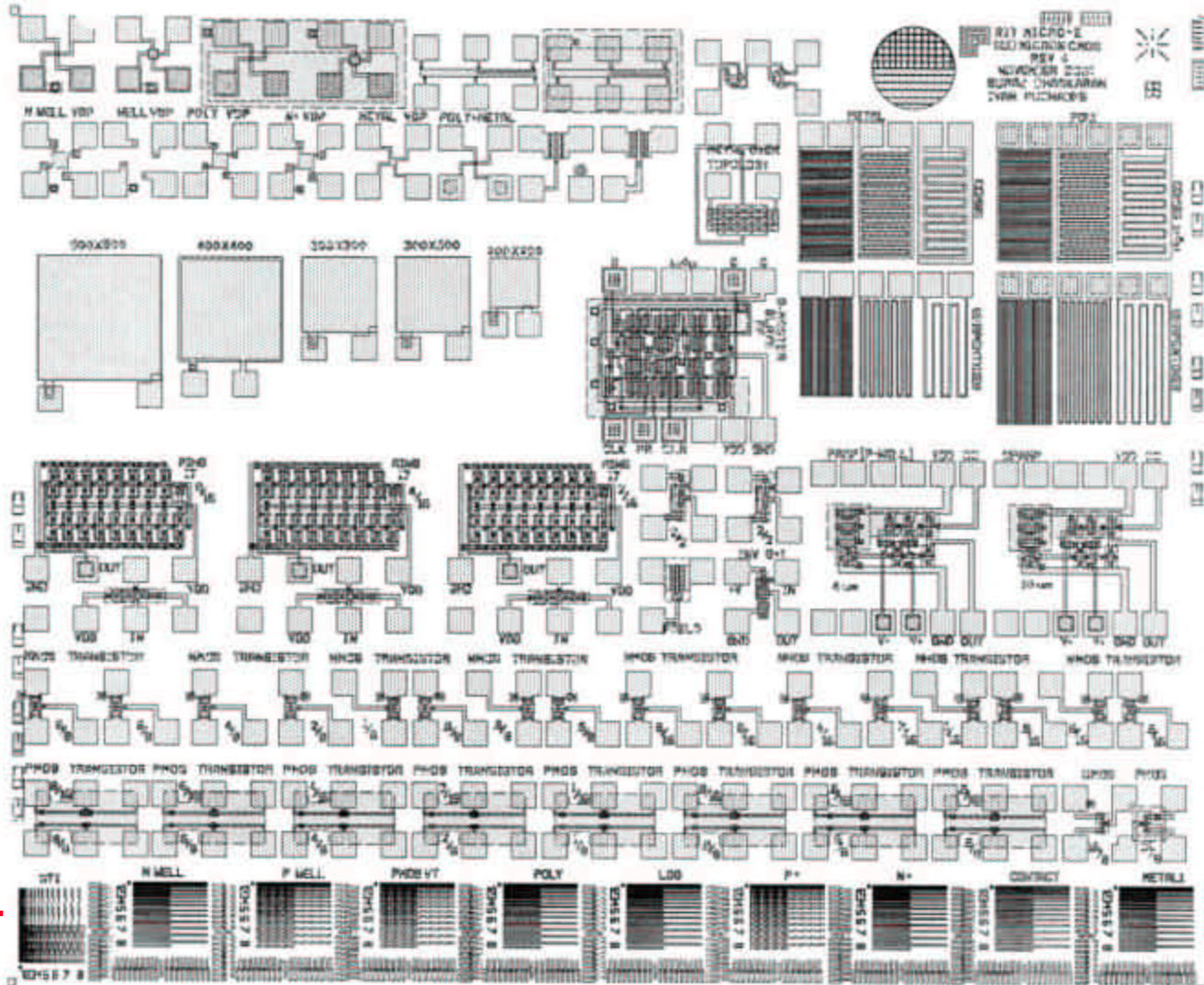


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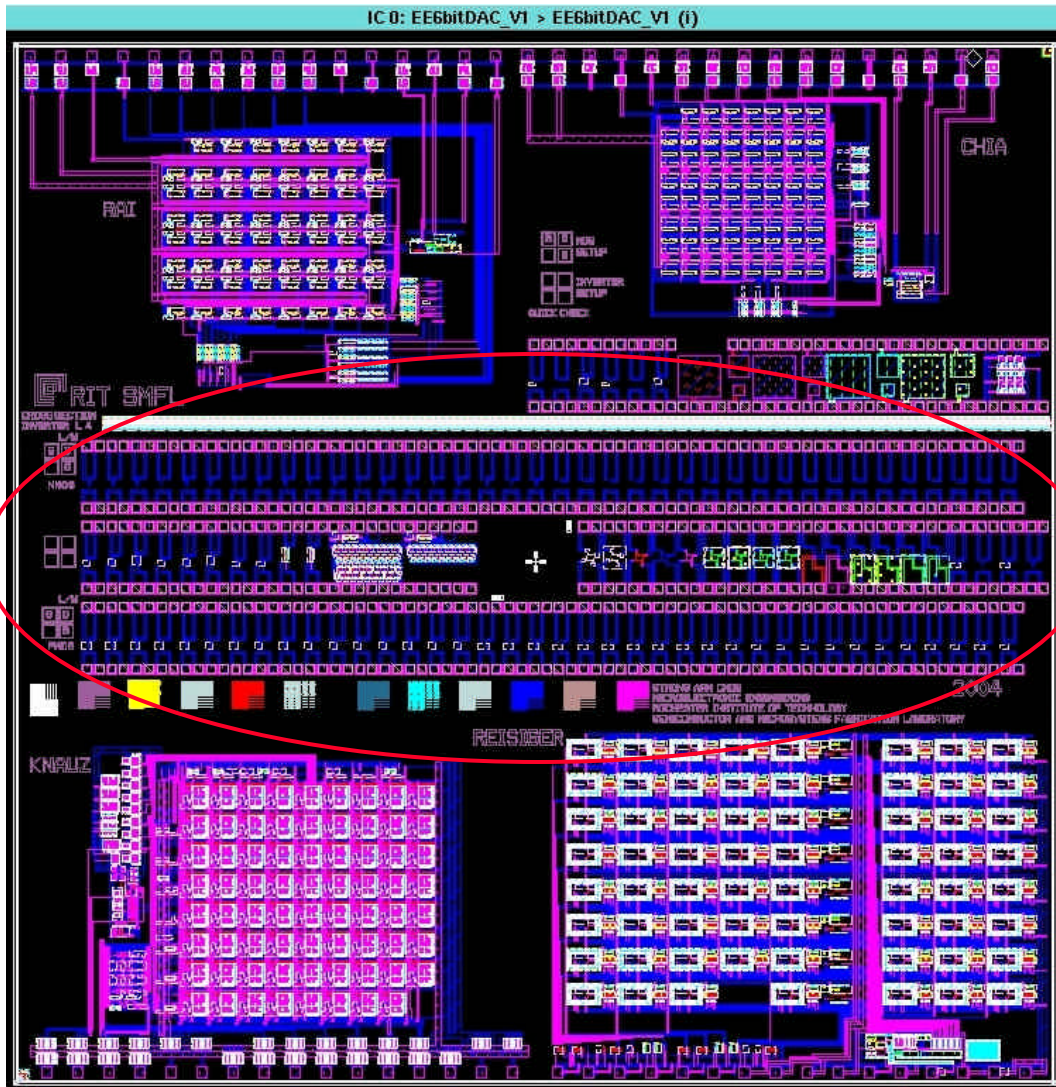
*SPICE PARAMETRIC CMOS TEST CHIP*



ADVANCED CMOS TEST CHIP



# DAC 2003 PROJECT CHIP



# JOHN GAULT TEST CHIP

